

STS25NH3LL

N-CHANNEL 30V - 0.0032 Ω - 25A SO-8 STripFETTM III MOSFET FOR DC-DC CONVERSION

TYPE	V _{DSS}	R _{DS(on)}	I _D
STS25NH3LL	30 V	<0.0035 Ω	25 A

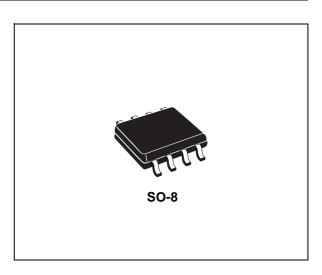
- TYPICAL $R_{DS}(on) = 0.0032 \Omega @ 10V$
- OPTIMAL R_{DS}(on) x Qg TRADE-OFF @ 4.5V
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED

DESCRIPTION

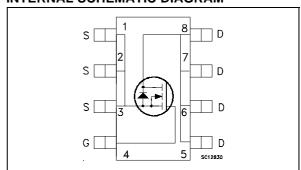
The STS25NH3LL utilizes the latest advanced design rules of ST's propetary STripFETTM technology. This novel 0.6μ process coupled to unique metalization techniques re alizes the most advanced low voltage MOSFET in SO-8 ever produced. It is therefore suit able for the most demanding DC-DC converter applications where high efficiency is to be achived at high output current.

APPLICATIONS

- DC-DC CONVERTERS FOR TELECOM AND NOTEBOOK CPU CORE
- SYNCHRONOUS RECTIFIER



INTERNAL SCHEMATIC DIAGRAM



Ordering Information

SALES TYPE	MARKING	PACKAGE	PACKAGING
STS25NH3LL	S25NH3LL	SO-8	TAPE & REEL

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	30	V
V _{GS}	Gate- source Voltage	± 18	V
I _D	Drain Current (continuous) at T _C = 25°C	25	Α
I _D	Drain Current (continuous) at T _C = 100°C	18	Α
I _{DM} (•)	Drain Current (pulsed)	100	Α
E _{AS} (1)	Single Pulse Avalanche Energy	200	mJ
P _{tot}	Total Dissipation at T _C = 25°C	3.2	W

^(•) Pulse width limited by safe operating area.

(1) Starting $T_i = 25 \text{ °C}$ $I_D = 12.5 \text{A}$ $V_{DD} = 30 \text{V}$

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THERMAL DATA

Rthj-amb Rthj-lead T _j T _{stq}	(*)Thermal Resistance Junction-ambient Max Thermal Resistance Junction-leads Max Maximum Operating Junction Temperature Storage Temperature	47 16 -55 to 175 -55 to 175	°C/W °C/W °C/W	
rstg	Storage Temperature	-55 to 175		

^(*) When Mounted on 1 inch² FR-4 board, 2 oz of Cu and t \leq 10 sec.

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	$V_{DS} = Max Rating$ $V_{DS} = Max Rating T_C = 125^{\circ}C$			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 18 V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	1			V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V V _{GS} = 4.5 V	I _D = 12.5 A I _D = 12.5 A		0.0032 0.004	0.0035 0.005	Ω Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	$V_{DS} = 10 \text{ V}$ $I_D = 12.5 \text{ A}$		30		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$		4450 655 50		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{aligned} V_{DD} &= 15 \text{ V} & I_D &= 12.5 \text{ A} \\ R_G &= 4.7 \ \Omega & V_{GS} &= 10 \text{ V} \\ \text{(Resistive Load, Figure 1)} \end{aligned}$		18 50		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V_{DD} =15V I_{D} =25A V_{GS} =4.5 V (see test circuit, Figure 2)		30 12.5 10	40	nC nC nC

SWITCHING OFF

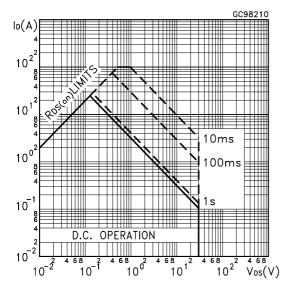
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	$\begin{array}{ccc} V_{DD} = 15 \ V & I_D = 12.5 \ A \\ R_G = 4.7 \Omega, & V_{GS} = 10 \ V \\ (Resistive Load, Figure 3) \end{array}$		75 8		ns ns

SOURCE DRAIN DIODE

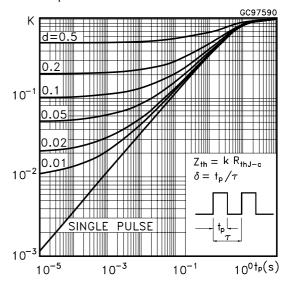
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM}	Source-drain Current Source-drain Current (pulsed)				25 100	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 25 A V _{GS} = 0			1.2	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 25 \text{ A}$ di/dt = 100A/ μ s $V_{DD} = 25 \text{ V}$ $T_j = 150^{\circ}\text{C}$ (see test circuit, Figure 3)		32 34 2.1		ns nC A

^(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

Safe Operating Area

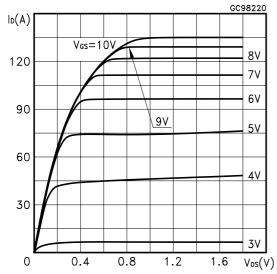


Thermal Impedance

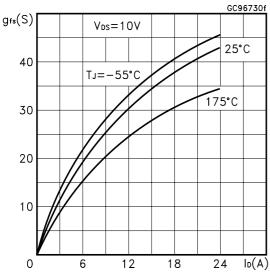


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Output Characteristics

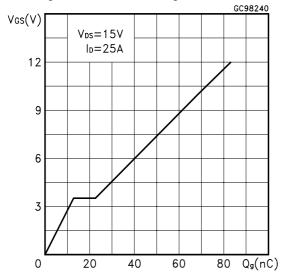


Transconductance

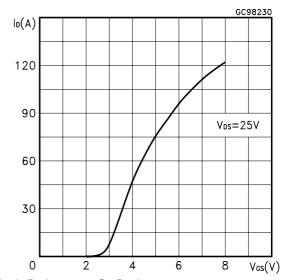


Gate Charge vs Gate-source Voltage

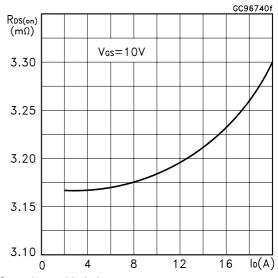
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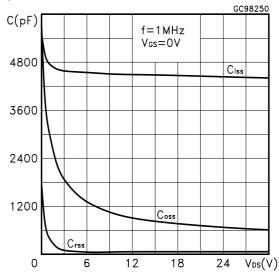
Transfer Characteristics



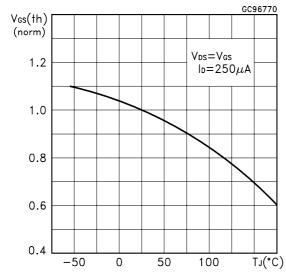
Static Drain-source On Resistance



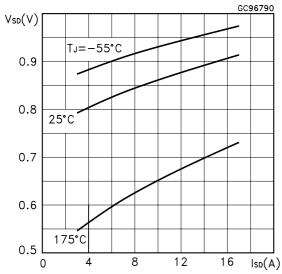
Capacitance Variations



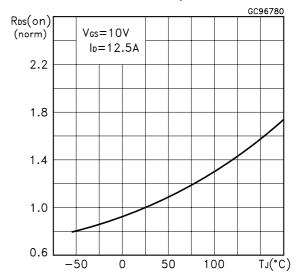
Normalized Gate Threshold Voltage vs Temperature



Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature.

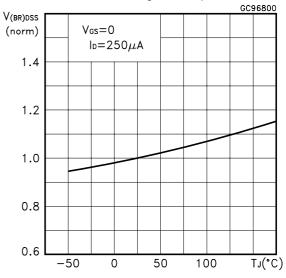


Fig. 1: Switching Times Test Circuits For Resistive Load

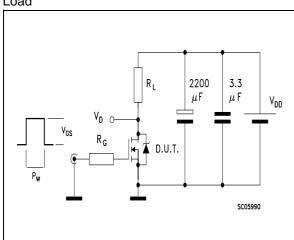


Fig. 2: Gate Charge test Circuit

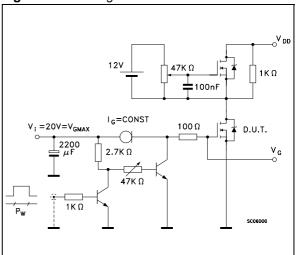
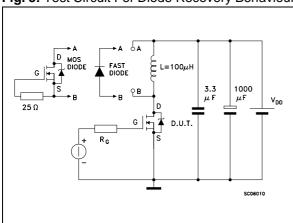
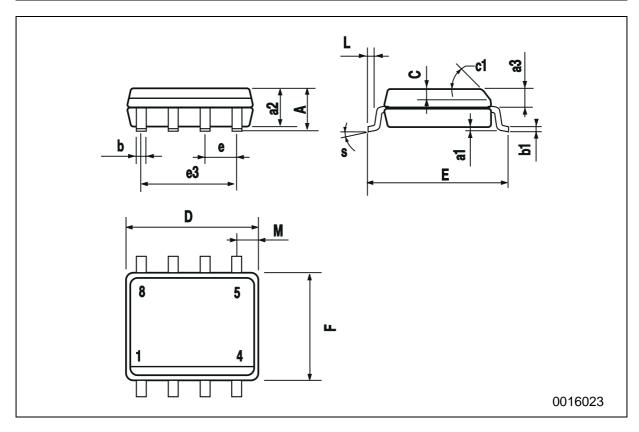


Fig. 3: Test Circuit For Diode Recovery Behaviour



SO-8 MECHANICAL DATA

DIM.		mm			inch			
DIWI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
А			1.75			0.068		
a1	0.1		0.25	0.003		0.009		
a2			1.65			0.064		
a3	0.65		0.85	0.025		0.033		
b	0.35		0.48	0.013		0.018		
b1	0.19		0.25	0.007		0.010		
С	0.25		0.5	0.010		0.019		
c1			45	(typ.)				
D	4.8		5.0	0.188		0.196		
Е	5.8		6.2	0.228		0.244		
е		1.27			0.050			
e3		3.81			0.150			
F	3.8		4.0	0.14		0.157		
L	0.4		1.27	0.015		0.050		
М			0.6			0.023		
S		8 (max.)						



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